Source of uncertainty	Process	Rate
Trigger selection	Simulated samples	2%
$m_{4\ell}$ resolution	Higgs boson	20%
$h \to ZZ \to 4\ell$ branching fraction	Higgs boson	2%
$gg \to ZZ$ NNLO to LO K factor	$gg \to ZZ$ bkg.	10%
Genuine p_T^{miss}	Simulated samples (Shape)	7–26%
Mismeasured p_T^{miss}	Z+Xbkg. (Shape)	2–30%
Z+Xbkg. yield	Z+Xbkg. (Yield)	36–43%
t$\bar{t}$+Vbkg. yield	t$\bar{t}$+Vbkg.	27–34%